

# Innovating with Advanced PDKs

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- **SER - (Soft Error Rate) – Detection and Analysis of Vulnerability of Si to radiation**
  - At leading edge geometries, Neutrons and Alpha particles causes distorted behavior in silicon
  - Effects need to be modeled and analyzed
- **GLOBALFOUNDRIES Collaborates with iROC Technologies**
  - Define and Develop FIT (Failure in Time) models for 28nm and 20nm PDKs starting 2H 2011
- **GLOBALFOUNDRIES will include the Process Response Model for the TFIT (Transistor FIT) software from iROC to be used with customer schematic and layout for current spike induction and analysis**